MC14001B Series

B-Suffix Series CMOS Gates

MC14001B, MC14011B, MC14023B, MC14025B, MC14071B, MC14073B, MC14081B, MC14082B

ON Semiconductor®

The B Series logic gates are constructed with P and N channel enhancement mode devices in a single monolithic structure (Complementary MOS). Their primary use is where low power dissipation and/or high noise immunity is desired.

Features

- Supply Voltage Range = 3.0 Vdc to 18 Vdc
- All Outputs Buffered
- Capable of Driving Two Low−power TTL Loads or One Low−power Schottky TTL Load Over the Rated Temperature Range.
- Double Diode Protection on All Inputs Except: Triple Diode Protection on MC14011B and MC14081B
- Pin−for−Pin Replacements for Corresponding CD4000 Series B Suffix Devices
- Pb−Free Packages are Available

MAXIMUM RATINGS (Voltages Referenced to V_{SS})

Symbol	Parameter	Value	Unit
V_{DD}	DC Supply Voltage Range	−0.5 to +18.0	V
V_{in}, V_{out}	Input or Output Voltage Range (DC or Transient)	−0.5 to V_{DD} + 0.5	V
I_{in}, I_{out}	Input or Output Current (DC or Transient) per Pin	±10	mA
P_D	Power Dissipation, per Package (Note 1)	500	mW
T_A	Ambient Temperature Range	−55 to +125	°C
T_{stg}	Storage Temperature Range	−65 to +150	°C
T_L	Lead Temperature (8−Second Soldering)	260	°C

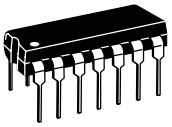
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Temperature Derating:
   Plastic “P and D/DW” Packages: − 7.0 mW/°C From 65°C To 125°C

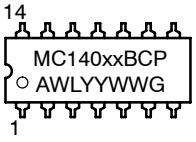
This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high−impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range $V_{SS} \le (V_{in}$ or $V_{out}) \le V_{DD}$.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either V_{SS} or V_{DD}). Unused outputs must be left open.

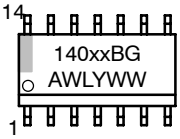
MARKING DIAGRAMS



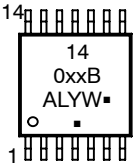
PDIP−14
P SUFFIX
CASE 646

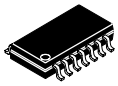


SOIC−14
D SUFFIX
CASE 751A

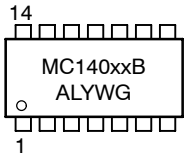


TSSOP−14
DT SUFFIX
CASE 948G





SOEIAJ−14
F SUFFIX
CASE 965



xx = Specific Device Code
A = Assembly Location
WL, L = Wafer Lot
YY, Y = Year
WW, W = Work Week
G or ▪ = Pb−Free Package
(Note: Microdot may be in either location)

DEVICE INFORMATION

Device	Description
MC14001B	Quad 2−Input NOR Gate
MC14011B	Quad 2−Input NAND Gate
MC14023B	Triple 3−Input NAND Gate
MC14025B	Triple 3−Input NOR Gate
MC14071B	Quad 2−Input OR Gate
MC14073B	Triple 3−Input AND Gate
MC14081B	Quad 2−Input AND Gate
MC14082B	Dual 4−Input AND Gate

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 8 of this data sheet.

Publication Order Number:
MC14001B/D

ELECTRICAL CHARACTERISTICS (Voltages Referenced to V_{SS})

Characteristic	Symbol	V_{DD} Vdc	– 55°C Min	– 55°C Max	25°C Min	25°C Typ (2)	25°C Max	125°C Min	125°C Max	Unit
Output Voltage "0" Level	V_{OL}	5.0	–	0.05	–	0	0.05	–	0.05	Vdc
V_{in} = V_{DD} or 0		10	–	0.05	–	0	0.05	–	0.05	
		15	–	0.05	–	0	0.05	–	0.05	
"1" Level	V_{OH}	5.0	4.95	–	4.95	5.0	–	4.95	–	Vdc
V_{in} = 0 or V_{DD}		10	9.95	–	9.95	10	–	9.95	–	
		15	14.95	–	14.95	15	–	14.95	–	
Input Voltage "0" Level	V_{IL}									Vdc
(V_O = 4.5 or 0.5 Vdc)		5.0	–	1.5	–	2.25	1.5	–	1.5	
(V_O = 9.0 or 1.0 Vdc)		10	–	3.0	–	4.50	3.0	–	3.0	
(V_O = 13.5 or 1.5 Vdc)		15	–	4.0	–	6.75	4.0	–	4.0	
"1" Level	V_{IH}									Vdc
(V_O = 0.5 or 4.5 Vdc)		5.0	3.5	–	3.5	2.75	–	3.5	–	
(V_O = 1.0 or 9.0 Vdc)		10	7.0	–	7.0	5.50	–	7.0	–	
(V_O = 1.5 or 13.5 Vdc)		15	11	–	11	8.25	–	11	–	
Output Drive Current	I_{OH}									mAdc
(V_{OH} = 2.5 Vdc) Source		5.0	– 3.0	–	– 2.4	– 4.2	–	– 1.7	–	
(V_{OH} = 4.6 Vdc)		5.0	– 0.64	–	– 0.51	– 0.88	–	– 0.36	–	
(V_{OH} = 9.5 Vdc)		10	– 1.6	–	– 1.3	– 2.25	–	– 0.9	–	
(V_{OH} = 13.5 Vdc)		15	– 4.2	–	– 3.4	– 8.8	–	– 2.4	–	
(V_{OL} = 0.4 Vdc) Sink	I_{OL}	5.0	0.64	–	0.51	0.88	–	0.36	–	mAdc
(V_{OL} = 0.5 Vdc)		10	1.6	–	1.3	2.25	–	0.9	–	
(V_{OL} = 1.5 Vdc)		15	4.2	–	3.4	8.8	–	2.4	–	
Input Current	I_{in}	15	–	± 0.1	–	±0.00001	± 0.1	–	± 1.0	μAdc
Input Capacitance (V_{in} = 0)	C_{in}	–	–	–	–	5.0	7.5	–	–	pF
Quiescent Current (Per Package)	I_{DD}	5.0	–	0.25	–	0.0005	0.25	–	7.5	μAdc
		10	–	0.5	–	0.0010	0.5	–	15	
		15	–	1.0	–	0.0015	1.0	–	30	
Total Supply Current (3) (4) (Dynamic plus Quiescent, Per Gate, C_L = 50 pF)	I_T	5.0	I_T = (0.3 μA/kHz) f + I_{DD}/N							μAdc
		10	I_T = (0.6 μA/kHz) f + I_{DD}/N							
		15	I_T = (0.9 μA/kHz) f + I_{DD}/N							

2. Data labelled "Typ" is not to be used for design purposes but is intended as an indication of the IC's potential performance.
3. The formulas given are for the typical characteristics only at 25°C.
4. To calculate total supply current at loads other than 50 pF:

$$I_T(C_L) = I_T(50\ pF) + (C_L - 50)\ Vfk$$

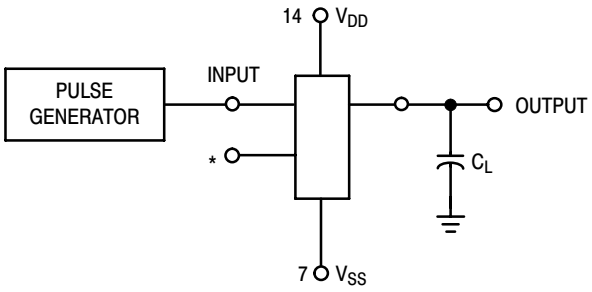
where: I_T is in μA (per package), C_L in pF, V = (V_{DD} – V_{SS}) in volts, f in kHz is input frequency, and k = 0.001 x the number of exercised gates per package.

B−SERIES GATE SWITCHING TIMES

SWITCHING CHARACTERISTICS [5] (C_L = 50 pF, T_A = 25°C)

Characteristic	Symbol	V_{DD} Vdc	Min	Typ [6]	Max	Unit
Output Rise Time, All B−Series Gates	t_{TLH}					ns
t_{TLH} = (1.35 ns/pF) C_L + 33 ns		5.0	–	100	200	
t_{TLH} = (0.60 ns/pF) C_L + 20 ns		10	–	50	100	
t_{TLH} = (0.40 ns/PF) C_L + 20 ns		15	–	40	80	
Output Fall Time, All B−Series Gates	t_{THL}					ns
t_{THL} = (1.35 ns/pF) C_L + 33 ns		5.0	–	100	200	
t_{THL} = (0.60 ns/pF) C_L + 20 ns		10	–	50	100	
t_{THL} = (0.40 ns/pF) C_L + 20 ns		15	–	40	80	
Propagation Delay Time	t_{PLH}, t_{PHL}					ns
MC14001B, MC14011B only						
t_{PLH}, t_{PHL} = (0.90 ns/pF) C_L + 80 ns		5.0	–	125	250	
t_{PLH}, t_{PHL} = (0.36 ns/pF) C_L + 32 ns		10	–	50	100	
t_{PLH}, t_{PHL} = (0.26 ns/pF) C_L + 27 ns		15	–	40	80	
All Other 2, 3, and 4 Input Gates						
t_{PLH}, t_{PHL} = (0.90 ns/pF) C_L + 115 ns		5.0	–	160	300	
t_{PLH}, t_{PHL} = (0.36 ns/pF) C_L + 47 ns		10	–	65	130	
t_{PLH}, t_{PHL} = (0.26 ns/pF) C_L + 37 ns		15	–	50	100	
8−Input Gates (MC14068B, MC14078B)						
t_{PLH}, t_{PHL} = (0.90 ns/pF) C_L + 155 ns		5.0	–	200	350	
t_{PLH}, t_{PHL} = (0.36 ns/pF) C_L + 62 ns		10	–	80	150	
t_{PLH}, t_{PHL} = (0.26 ns/pF) C_L + 47 ns		15	–	60	110	

5. The formulas given are for the typical characteristics only at 25°C.
6. Data labelled “Typ” is not to be used for design purposes but is intended as an indication of the IC’s potential performance.



*All unused inputs of AND, NAND gates must be connected to V_{DD}.
All unused inputs of OR, NOR gates must be connected to V_{SS}.

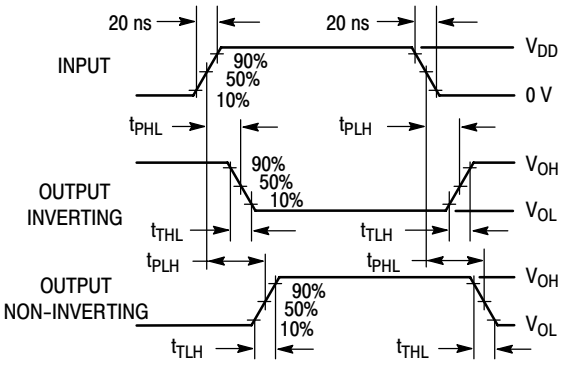


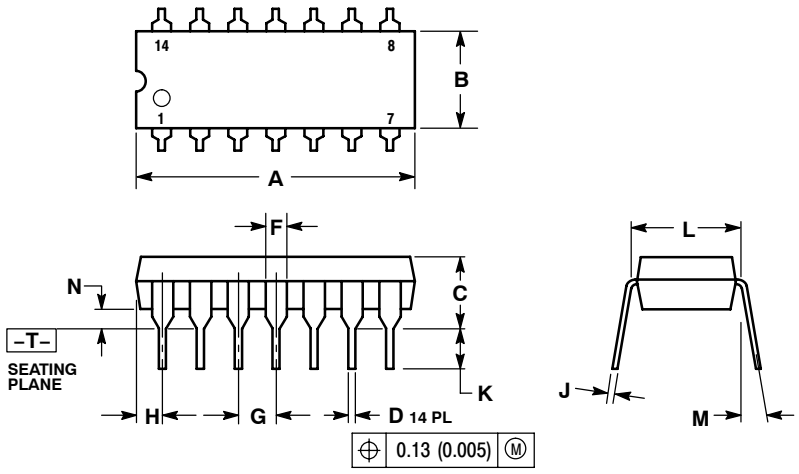
Figure 1. Switching Time Test Circuit and Waveforms

ORDERING INFORMATION

Device	Package	Shipping†
MC14001BCP	PDIP−14	25 Units / Rail
MC14001BCPG	PDIP−14 (Pb−Free)	
MC14001BD	SOIC−14	55 Units / Rail
MC14001BDG	SOIC−14 (Pb−Free)	
MC14001BDR2	SOIC−14	2500 Units / Tape & Reel
MC14001BDR2G	SOIC−14 (Pb−Free)	
MC14001BDTR2	TSSOP−14*	
MC14001BDTR2G	TSSOP−14* (Pb−Free)	
MC14001BFEL	SOEIAJ−14	2000 Units / Tape & Reel
MC14001BFELG	SOEIAJ−14 (Pb−Free)	
MC14011BCP	PDIP−14	25 Units / Rail
MC14011BCPG	PDIP−14 (Pb−Free)	
MC14011BD	SOIC−14	55 Units / Rail
MC14011BDG	SOIC−14 (Pb−Free)	
MC14011BDR2	SOIC−14	2500 Units / Tape & Reel
MC14011BDR2G	SOIC−14 (Pb−Free)	
MC14011BDTR2	TSSOP−14*	
MC14011BDTR2G	TSSOP−14* (Pb−Free)	
MC14011BF	SOEIAJ−14	50 Units / Rail
MC14011BFG	SOEIAJ−14 (Pb−Free)	
MC14011BFEL	SOEIAJ−14	2000 Units / Tape & Reel
MC14011BFELG	SOEIAJ−14 (Pb−Free)	
MC14023BCP	PDIP−14	25 Units / Rail
MC14023BCPG	PDIP−14 (Pb−Free)	
MC14023BD	SOIC−14	55 Units / Rail
MC14023BDG	SOIC−14 (Pb−Free)	
MC14023BDR2	SOIC−14	2500 Units / Tape & Reel
MC14023BDR2G	SOIC−14 (Pb−Free)	
MC14023BFEL	SOEIAJ−14	2000 Units / Tape & Reel
MC14023BFELG	SOEIAJ−14 (Pb−Free)	

PACKAGE DIMENSIONS

PDIP−14
CASE 646−06
ISSUE P

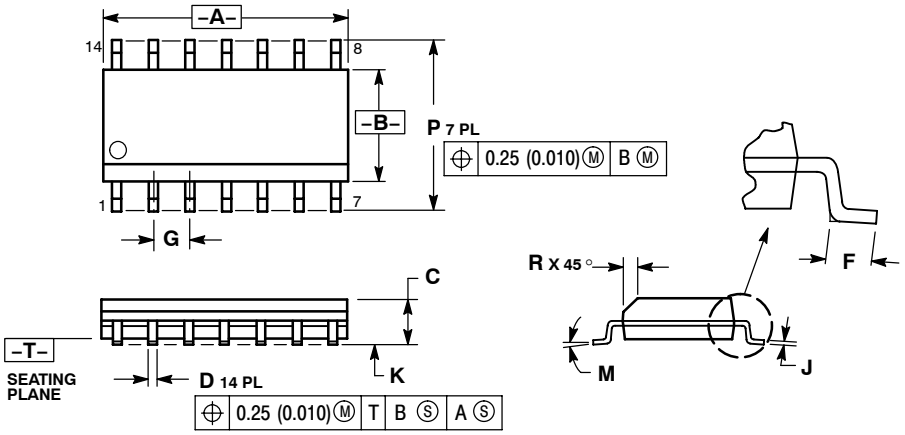


NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
5. ROUNDED CORNERS OPTIONAL.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.715	0.770	18.16	19.56
B	0.240	0.260	6.10	6.60
C	0.145	0.185	3.69	4.69
D	0.015	0.021	0.38	0.53
F	0.040	0.070	1.02	1.78
G	0.100 BSC		2.54 BSC	
H	0.052	0.095	1.32	2.41
J	0.008	0.015	0.20	0.38
K	0.115	0.135	2.92	3.43
L	0.290	0.310	7.37	7.87
M	−−−	10 °	−−−	10 °
N	0.015	0.039	0.38	1.01

PACKAGE DIMENSIONS

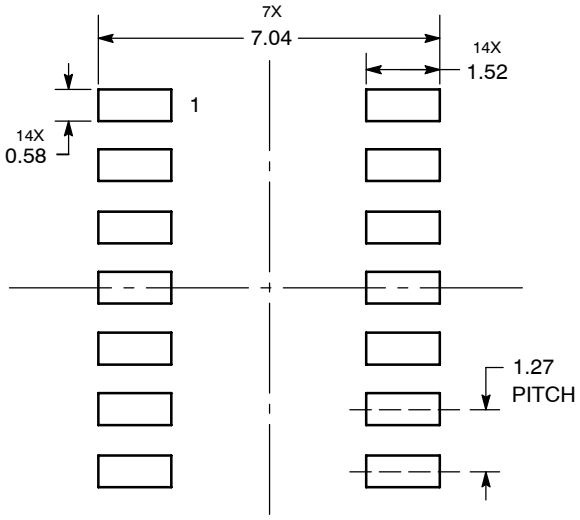
SOIC−14
CASE 751A−03
ISSUE H



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	8.55	8.75	0.337	0.344
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27 BSC		0.050 BSC	
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0 °	7 °	0 °	7 °
P	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.